

# 74ALVT16821

20-bit bus interface D-type flip-flop; positive-edge trigger;  
3-state

Rev. 4 — 22 January 2018

Product data sheet

## 1 General description

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The 74ALVT16821 high-performance BiCMOS device combines low static and dynamic power dissipation with high speed and high output drive. It is designed for  $V_{CC}$  operation at 2.5 V or 3.3 V with I/O compatibility to 5 V.

The 74ALVT16821 has two 10-bit, edge triggered registers, with each register coupled to a 3-state output buffer. The two sections of each register are controlled independently by the clock ( $nCP$ ) and output enable ( $n\overline{OE}$ ) control gates.

Each register is fully edge triggered. The state of each D input, one set-up time before the LOW-to-HIGH clock transition, is transferred to the corresponding flip-flops Q output.

The 3-state output buffers are designed to drive heavily loaded 3-state buses, MOS memories, or MOS microprocessors.

The active low output enable ( $n\overline{OE}$ ) controls all ten 3-state buffers independent of the register operation. When  $n\overline{OE}$  is LOW, the data in the register appears at the outputs. When  $n\overline{OE}$  is HIGH, the outputs are in high-impedance OFF-state, which means they will neither drive nor load the bus.

## 2 Features and benefits

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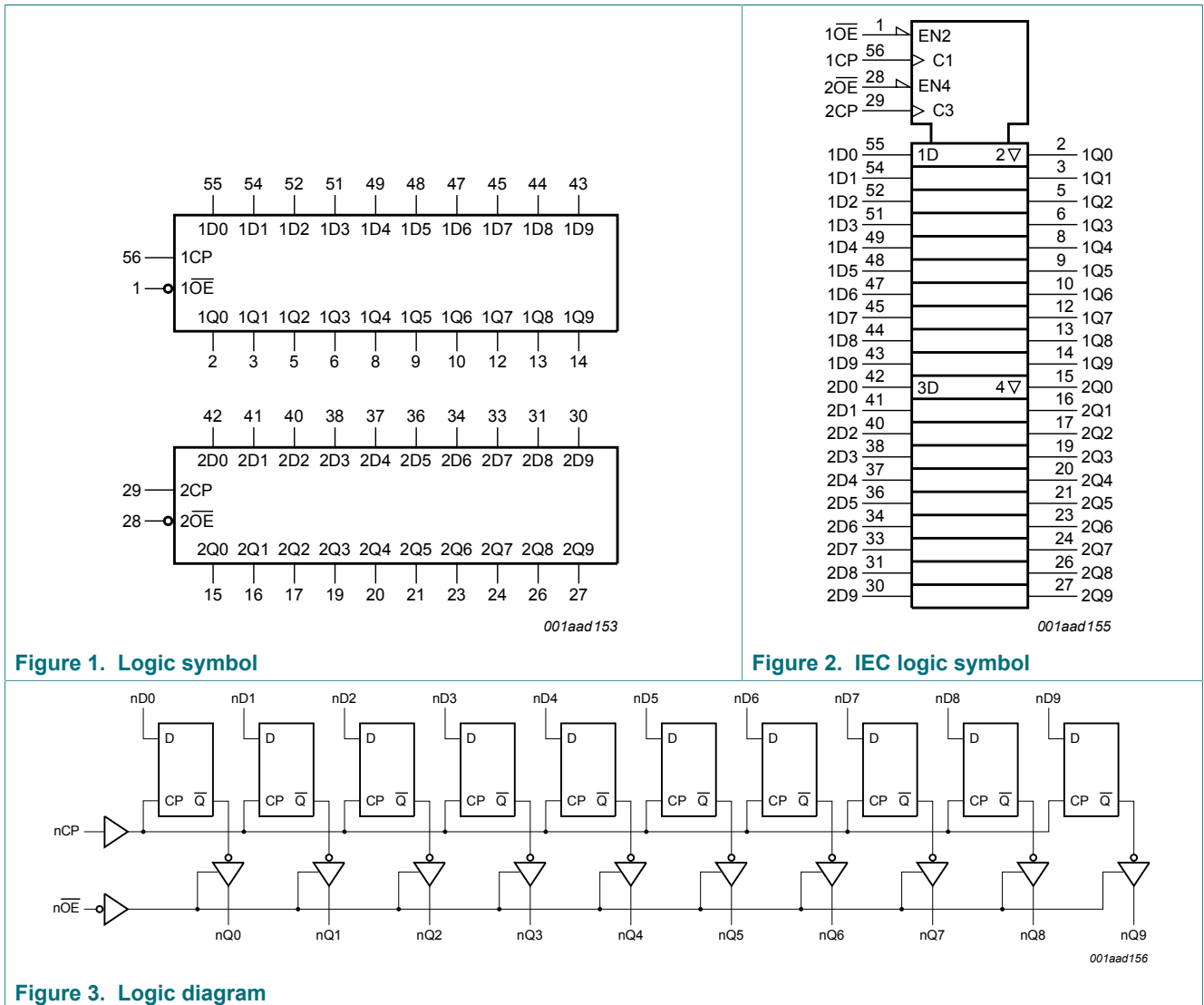
- 20-bit positive-edge triggered register
- 5 V I/O compatible
- Multiple  $V_{CC}$  and GND pins minimize switching noise
- Bus hold data inputs eliminate the need for external pull-up resistors to hold unused inputs
- Live insertion and extraction permitted
- Power-up reset
- Power-up 3-state
- Output capability: +64 mA and -32 mA
- Latch-up protection:
  - JESD78: exceeds 500 mA
- ESD protection:
  - MIL STD 883, method 3015: exceeds 2000 V
  - MM: exceeds 200 V

### 3 Ordering information

Table 1. Ordering information

Type number	Package			Version
	Temperature range	Name	Description	
74ALVT16821DGG	-40 °C to +85 °C	TSSOP56	plastic thin shrink small outline package; 56 leads; body width 6.1 mm	SOT364-1

### 4 Functional diagram



## 5 Pinning information

### 5.1 Pinning

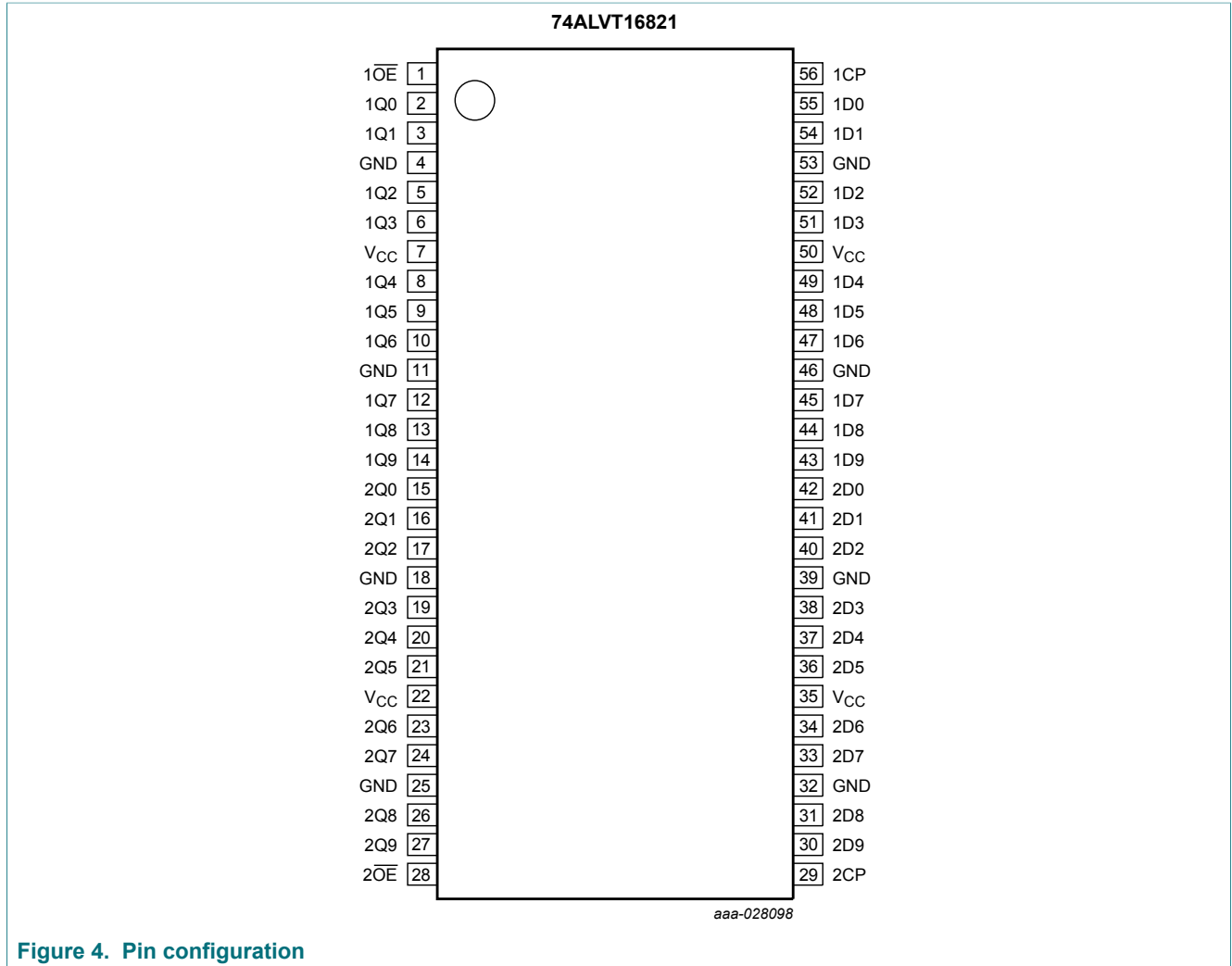


Figure 4. Pin configuration

## 5.2 Pin description

Table 2. Pin description

Symbol	Pin	Description
1D0, 1D1, 1D2, 1D3, 1D4, 1D5, 1D6, 1D7, 1D8, 1D9	55, 54, 52, 51, 49, 48, 47, 45, 44, 43	data inputs
1Q0, 1Q1, 1Q2, 1Q3, 1Q4, 1Q5, 1Q6, 1Q7, 1Q8, 1Q9	2, 3, 5, 6, 8, 9, 10, 12, 13, 14	data outputs
2D0, 2D1, 2D2, 2D3, 2D4, 2D5, 2D6, 2D7, 2D8, 2D9	42, 41, 40, 38, 37, 36, 34, 33, 31, 30	data inputs
2Q0, 2Q1, 2Q2, 2Q3, 2Q4, 2Q5, 2Q6, 2Q7, 2Q8, 2Q9	15, 16, 17, 19, 20, 21, 23, 24, 26, 27	data outputs
1 $\overline{OE}$ , 2 $\overline{OE}$	1, 28	output enable inputs (active LOW)
1CP, 2CP	56, 29	clock pulse inputs (active rising edge)
GND	4, 11, 18, 25, 32, 39, 46, 53	ground (0 V)
V <sub>CC</sub>	7, 22, 35, 50	supply voltage

## 6 Functional description

Table 3. Function table <sup>[1]</sup>

Operating mode	Input			Internal register	Output
	nOE	nCP	nDn		
Load and read register	L	↑	l	L	L
	L	↑	h	H	H
Hold	L	NC	X	NC	NC
Disable outputs	H	NC	X	NC	Z
	H	↑	nDn	nDn	Z

- [1] H = HIGH voltage level;  
h = HIGH voltage level one set-up time prior to the LOW-to-HIGH clock transition;  
L = LOW voltage level;  
l = LOW voltage level one set-up time prior to the LOW-to-HIGH clock transition;  
NC = no change;  
X = don't care;  
Z = high-impedance OFF-state;  
↑ = LOW-to-HIGH clock transition.

## 7 Limiting values

**Table 4. Limiting values**

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{CC}$	supply voltage		-0.5	+4.6	V
$V_I$	input voltage		[1] -1.2	+7.0	V
$V_O$	output voltage	output in OFF-state or HIGH-state	[1] -0.5	+7.0	V
$I_{IK}$	input clamping current	$V_I < 0$ V	-	-50	mA
$I_{OK}$	output clamping current	$V_O < 0$ V	-	-50	mA
$I_O$	output current	output in LOW-state	-	128	mA
		output in HIGH-state	-	-64	mA
$T_{stg}$	storage temperature		-65	+150	°C
$T_j$	junction temperature		[2] -	150	°C

[1] The input and output negative voltage ratings may be exceeded if the input and output clamp current ratings are observed.

[2] The performance capability of a high-performance integrated circuit in conjunction with its thermal environment can create junction temperatures which are detrimental to reliability.

## 8 Recommended operating conditions

**Table 5. Recommended operating conditions**

Symbol	Parameter	Conditions	$V_{CC} = 2.5\text{ V} \pm 0.2\text{ V}$		$V_{CC} = 3.3\text{ V} \pm 0.3\text{ V}$		Unit
			Min	Max	Min	Max	
$V_{CC}$	supply voltage		2.3	2.7	3.0	3.6	V
$V_I$	input voltage		0	5.5	0	5.5	V
$I_{OH}$	HIGH-level output current		-	-8	-	-32	mA
$I_{OL}$	LOW-level output current	none	-	8	-	32	mA
		current duty cycle $\leq 50\%$ ; $f \geq 1$ kHz	-	24	-	64	mA
$\Delta t/\Delta V$	input transition rise and fall rate	outputs enabled	-	10	-	10	ns/V
$T_{amb}$	ambient temperature	free-air	-40	+85	-40	+85	°C

## 9 Static characteristics

**Table 6. Static characteristics**

At recommended operating conditions;  $T_{amb} = -40\text{ °C}$  to  $+85\text{ °C}$ ; voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	Min	Typ <sup>[1]</sup>	Max	Unit
<b><math>V_{CC} = 2.5\text{ V} \pm 0.2\text{ V}</math></b>						
$V_{IK}$	input clamping voltage	$V_{CC} = 2.3\text{ V}$ ; $I_{IK} = -18\text{ mA}$	-	-0.85	-1.2	V
$V_{IH}$	HIGH-level input voltage		1.7	-	-	V
$V_{IL}$	LOW-level input voltage		-	-	0.7	V
$V_{OH}$	HIGH-level output voltage	$V_{CC} = 2.3\text{ V}$ to $3.6\text{ V}$ ; $I_O = -100\text{ }\mu\text{A}$	$V_{CC} - 0.2$	$V_{CC}$	-	V
		$V_{CC} = 2.3\text{ V}$ ; $I_O = -8\text{ mA}$	1.8	2.1	-	V
$V_{OL}$	LOW-level output voltage	$V_{CC} = 2.3\text{ V}$ ; $I_O = 100\text{ }\mu\text{A}$	-	0.07	0.2	V
		$V_{CC} = 2.3\text{ V}$ ; $I_O = 24\text{ mA}$	-	0.3	0.5	V
		$V_{CC} = 2.3\text{ V}$ ; $I_O = 8\text{ mA}$	-	-	0.4	V
$V_{OL(pu)}$	power-up LOW-level output voltage	$V_{CC} = 2.7\text{ V}$ ; $I_O = 1\text{ mA}$ ; $V_I = V_{CC}$ or GND <sup>[2]</sup>	-	-	0.55	V
$I_I$	input leakage current	all input pins				
		$V_{CC} = 0\text{ V}$ or $2.7\text{ V}$ ; $V_I = 5.5\text{ V}$ <sup>[3]</sup>	-	0.1	10	$\mu\text{A}$
		control pins				
		$V_{CC} = 2.7\text{ V}$ ; $V_I = V_{CC}$ or GND	-	0.1	$\pm 1$	$\mu\text{A}$
		data pins; <sup>[3]</sup>				
		$V_{CC} = 2.7\text{ V}$ ; $V_I = V_{CC}$	-	0.1	1	$\mu\text{A}$
	$V_{CC} = 2.7\text{ V}$ ; $V_I = 0\text{ V}$	-	0.1	-5	$\mu\text{A}$	
$I_{OFF}$	power-off leakage current	$V_{CC} = 0\text{ V}$ ; $V_I$ or $V_O = 0\text{ V}$ to $4.5\text{ V}$	-	0.1	$\pm 100$	$\mu\text{A}$
$I_{BHL}$	bus hold LOW current	data inputs; $V_{CC} = 2.3\text{ V}$ ; $V_I = 0.7\text{ V}$	-	90	-	$\mu\text{A}$
$I_{BHH}$	bus hold HIGH current	data inputs; $V_{CC} = 2.3\text{ V}$ ; $V_I = 1.7\text{ V}$	-	-10	-	$\mu\text{A}$
$I_{EX}$	external current	output in HIGH-state; $V_O = 5.5\text{ V}$ ; $V_{CC} = 2.3\text{ V}$	-	10	125	$\mu\text{A}$
$I_{O(pu/pd)}$	power-up/power-down output current	$V_{CC} \leq 1.2\text{ V}$ ; $V_O = 0.5\text{ V}$ to $V_{CC}$ ; $V_I = \text{GND}$ or $V_{CC}$ ; $n\text{OE} = \text{don't care}$ <sup>[4]</sup>	-	1	$\pm 100$	$\mu\text{A}$
$I_{OZ}$	OFF-state output current	$V_{CC} = 2.7\text{ V}$ ; $V_I = V_{IL}$ or $V_{IH}$				
		output HIGH-state; $V_O = 2.3\text{ V}$	-	0.5	5	$\mu\text{A}$
		output LOW-state; $V_O = 0.5\text{ V}$	-	0.5	-5	$\mu\text{A}$
$I_{CC}$	supply current	$V_{CC} = 2.7\text{ V}$ ; $V_I = \text{GND}$ or $V_{CC}$ ; $I_O = 0\text{ A}$				
		outputs HIGH-state	-	0.04	0.1	mA
		outputs LOW-state	-	2.3	4.5	mA
		outputs disabled <sup>[5]</sup>		0.04	0.1	mA
$\Delta I_{CC}$	additional supply current	per input pin; $V_{CC} = 2.3\text{ V}$ to $2.7\text{ V}$ ; one input at $V_{CC} - 0.6\text{ V}$ ; other inputs at $V_{CC}$ or GND <sup>[6]</sup>	-	0.04	0.4	mA
$C_I$	input capacitance	$V_I = 0\text{ V}$ or $V_{CC}$	-	3	-	pF
$C_O$	output capacitance	$V_O = 0\text{ V}$ or $V_{CC}$	-	9	-	pF

Symbol	Parameter	Conditions	Min	Typ <sup>[1]</sup>	Max	Unit
<b>V<sub>CC</sub> = 3.3 V ± 0.3 V</b>						
V <sub>IK</sub>	input clamping voltage	V <sub>CC</sub> = 3.0 V; I <sub>IK</sub> = -18 mA	-	-0.85	-1.2	V
V <sub>IH</sub>	HIGH-level input voltage		2.0	-	-	V
V <sub>IL</sub>	LOW-level input voltage		-	-	0.8	V
V <sub>OH</sub>	HIGH-level output voltage	V <sub>CC</sub> = 3.0 V to 3.6 V; I <sub>O</sub> = -100 μA	V <sub>CC</sub> - 0.2	V <sub>CC</sub>	-	V
		V <sub>CC</sub> = 3.0 V; I <sub>O</sub> = -32 mA	2.0	2.3	-	V
V <sub>OL</sub>	LOW-level output voltage	V <sub>CC</sub> = 3.0 V				
		I <sub>O</sub> = 100 μA	-	0.07	0.2	V
		I <sub>O</sub> = 16 mA	-	0.25	0.4	V
		I <sub>O</sub> = 32 mA	-	0.3	0.5	V
V <sub>OL(pu)</sub>	power-up LOW-level output voltage	V <sub>CC</sub> = 3.0 V; I <sub>O</sub> = 64 mA	-	0.4	0.55	V
		V <sub>CC</sub> = 3.6 V; I <sub>O</sub> = 1 mA; V <sub>I</sub> = V <sub>CC</sub> or GND <sup>[2]</sup>	-	-	0.55	V
I <sub>I</sub>	input leakage current	all input pins; <sup>[3]</sup>				
		V <sub>CC</sub> = 0 V or 3.6 V; V <sub>I</sub> = 5.5 V	-	0.1	10	μA
		control pins				
		V <sub>CC</sub> = 3.6 V; V <sub>I</sub> = V <sub>CC</sub> or GND	-	0.1	±1	μA
		data pins; <sup>[3]</sup>				
		V <sub>CC</sub> = 3.6 V; V <sub>I</sub> = V <sub>CC</sub>	-	0.5	1	μA
		V <sub>CC</sub> = 3.6 V; V <sub>I</sub> = 0 V	-	0.1	-5	μA
I <sub>OFF</sub>	power-off leakage current	V <sub>CC</sub> = 0 V; V <sub>I</sub> or V <sub>O</sub> = 0 V to 4.5 V	-	0.1	±100	μA
I <sub>BHL</sub>	bus hold LOW current	data inputs; V <sub>CC</sub> = 3 V; V <sub>I</sub> = 0.8 V	75	130	-	μA
I <sub>BHH</sub>	bus hold HIGH current	data inputs; V <sub>CC</sub> = 3 V; V <sub>I</sub> = 2.0 V	-75	-140	-	μA
I <sub>BHLO</sub>	bus hold LOW overdrive current	data inputs; V <sub>CC</sub> = 3.6 V; V <sub>I</sub> = 0 V to 3.6 V <sup>[7]</sup>	500	-	-	μA
I <sub>BHHO</sub>	bus hold HIGH overdrive current	data inputs; V <sub>CC</sub> = 3.6 V; V <sub>I</sub> = 0 V to 3.6 V <sup>[7]</sup>	-500	-	-	μA
I <sub>EX</sub>	external current	output in HIGH-state when V <sub>O</sub> > V <sub>CC</sub> ; V <sub>O</sub> = 5.5 V; V <sub>CC</sub> = 3.0 V	-	10	125	μA
I <sub>O(pu/pd)</sub>	power-up/power-down output current	V <sub>CC</sub> ≤ 1.2 V; V <sub>O</sub> = 0.5 V to V <sub>CC</sub> ; V <sub>I</sub> = GND or V <sub>CC</sub> ; n $\overline{OE}$ = don't care <sup>[8]</sup>	-	1	±100	μA
I <sub>OZ</sub>	OFF-state output current	V <sub>CC</sub> = 3.6 V; V <sub>I</sub> = V <sub>IL</sub> or V <sub>IH</sub>				
		output HIGH-state; V <sub>O</sub> = 3.0 V	-	0.5	5	μA
		output LOW-state; V <sub>O</sub> = 0.5 V	-	0.5	-5	μA
I <sub>CC</sub>	supply current	V <sub>CC</sub> = 3.6 V; V <sub>I</sub> = GND or V <sub>CC</sub> ; I <sub>O</sub> = 0 A				
		outputs HIGH-state	-	0.07	0.1	mA
		outputs LOW-state	-	5.1	7	mA
		outputs disabled <sup>[5]</sup>	-	0.07	0.1	mA

Symbol	Parameter	Conditions	Min	Typ <sup>[1]</sup>	Max	Unit
$\Delta I_{CC}$	additional supply current	per input pin; $V_{CC} = 3\text{ V to }3.6\text{ V}$ ; one input at $V_{CC} - 0.6\text{ V}$ ; other inputs at $V_{CC}$ or GND <sup>[6]</sup>	-	0.04	0.4	mA
$C_I$	input capacitance	$V_I = 0\text{ V or }V_{CC}$	-	3	-	pF
$C_O$	output capacitance	$V_O = 0\text{ V or }V_{CC}$	-	9	-	pF

- [1] All typical values for  $V_{CC} = 2.5\text{ V} \pm 0.2\text{ V}$  are measured at  $V_{CC} = 2.5\text{ V}$  and  $T_{amb} = 25\text{ }^\circ\text{C}$ .  
All typical values for  $V_{CC} = 3.3\text{ V} \pm 0.3\text{ V}$  are measured at  $V_{CC} = 3.3\text{ V}$  and  $T_{amb} = 25\text{ }^\circ\text{C}$ .
- [2] For valid test results, data must not be loaded into the flip-flops (or latches) after applying power.
- [3] Unused pins at  $V_{CC}$  or GND.
- [4] This parameter is valid for any  $V_{CC}$  between 0 V and 1.2 V with a transition time of up to 10 ms.  
From  $V_{CC} = 1.2\text{ V}$  to  $(2.5 \pm 0.2)\text{ V}$  a transition time of 100  $\mu\text{s}$  is permitted. This parameter is valid for  $T_{amb} = 25\text{ }^\circ\text{C}$  only.
- [5]  $I_{CC}$  with outputs disabled is measured with outputs pulled to  $V_{CC}$  or GND.
- [6] This is the increase in supply current for each input at the specified voltage level other than  $V_{CC}$  or GND.
- [7] This is the bus hold overdrive current required to force the input to the opposite logic state.
- [8] This parameter is valid for any  $V_{CC}$  between 0 V and 1.2 V with a transition time of up to 10 ms.  
From  $V_{CC} = 1.2\text{ V}$  to  $(3.3 \pm 0.3)\text{ V}$  a transition time of 100  $\mu\text{s}$  is permitted. This parameter is valid for  $T_{amb} = 25\text{ }^\circ\text{C}$  only.

## 10 Dynamic characteristics

**Table 7. Dynamic characteristics**

Voltages are referenced to GND (ground = 0 V);  $T_{amb} = -40\text{ }^\circ\text{C}$  to  $+85\text{ }^\circ\text{C}$ ; for test circuit see [Figure 8](#).

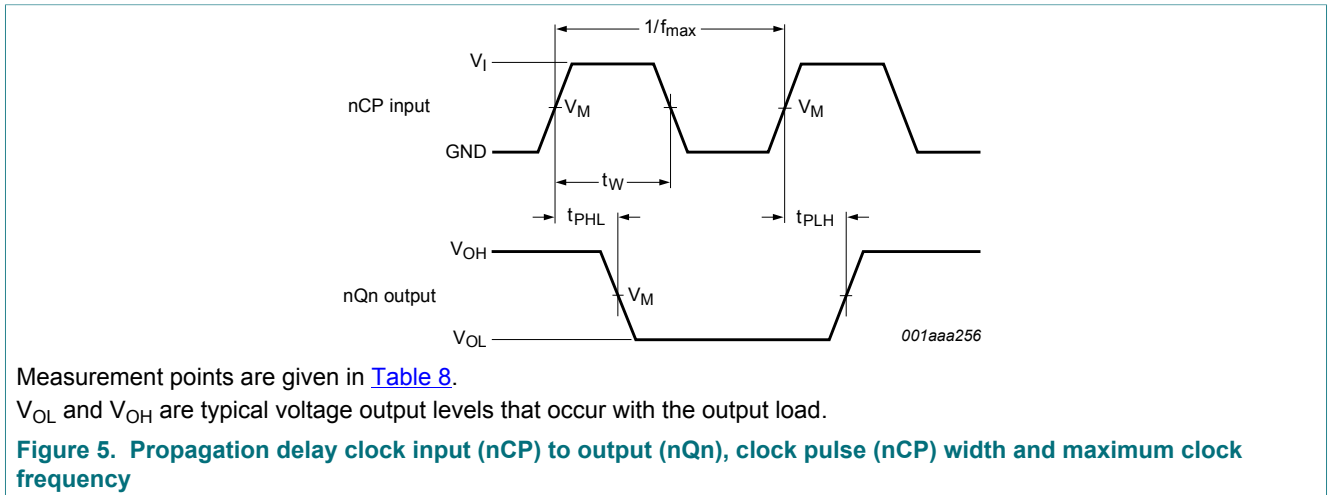
Symbol	Parameter	Conditions	Min	Typ <sup>[1]</sup>	Max	Unit
<b><math>V_{CC} = 2.5\text{ V} \pm 0.2\text{ V}</math></b>						
$t_{PLH}$	LOW to HIGH propagation delay	nCP to nQn; see <a href="#">Figure 5</a>	1.0	2.6	4.0	ns
$t_{PHL}$	HIGH to LOW propagation delay	nCP to nQn; see <a href="#">Figure 5</a>	1.0	2.7	4.4	ns
$t_{PZH}$	OFF-state to HIGH propagation delay	$n\overline{OE}$ to nQn; see <a href="#">Figure 7</a>	1.5	2.8	4.6	ns
$t_{PZL}$	OFF-state to LOW propagation delay	$n\overline{OE}$ to nQn; see <a href="#">Figure 7</a>	1.0	1.8	4.1	ns
$t_{PHZ}$	HIGH to OFF-state propagation delay	$n\overline{OE}$ to nQn; see <a href="#">Figure 7</a>	1.5	2.7	4.4	ns
$t_{PLZ}$	LOW to OFF-state propagation delay	$n\overline{OE}$ to nQn; see <a href="#">Figure 7</a>	1.0	2.1	3.3	ns
$t_{su}$	set-up time	nDn to nCP; HIGH; see <a href="#">Figure 6</a>	1.5	0.1	-	ns
		nDn to nCP; LOW; see <a href="#">Figure 6</a>	2.0	0.5	-	ns
$t_h$	hold time	nDn to nCP; HIGH; see <a href="#">Figure 6</a>	0.3	-0.5	-	ns
		nDn to nCP; LOW; see <a href="#">Figure 6</a>	0.5	-0.1	-	ns
$t_W$	pulse width	nCP HIGH; see <a href="#">Figure 5</a>	1.5	-	-	ns
		nCP LOW	1.5	-	-	ns
$f_{max}$	maximum frequency	nCP; see <a href="#">Figure 5</a>	150	-	-	MHz

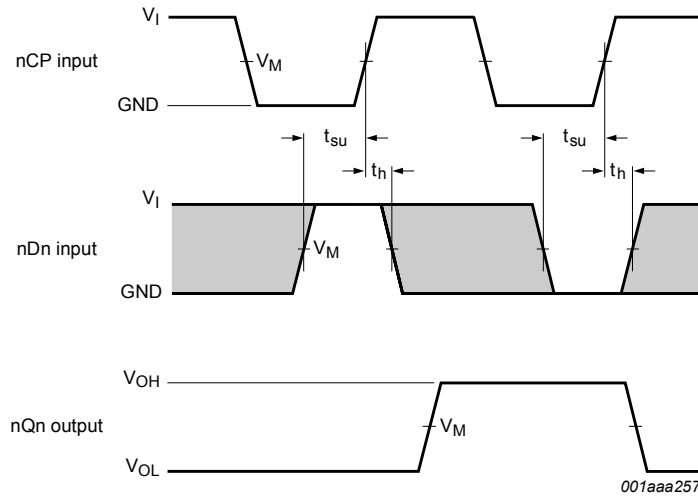


Symbol	Parameter	Conditions	Min	Typ <sup>[1]</sup>	Max	Unit
<b>V<sub>CC</sub> = 3.3 V ± 0.3 V</b>						
t <sub>PLH</sub>	LOW to HIGH propagation delay	nCP to nQn; see <a href="#">Figure 5</a>	0.5	1.7	3.0	ns
t <sub>PHL</sub>	HIGH to LOW propagation delay	nCP to nQn; see <a href="#">Figure 5</a>	0.5	1.8	3.2	ns
t <sub>PZH</sub>	OFF-state to HIGH propagation delay	n $\overline{OE}$ to nQn; see <a href="#">Figure 7</a>	1.0	2.1	3.5	ns
t <sub>PZL</sub>	OFF-state to LOW propagation delay	n $\overline{OE}$ to nQn; see <a href="#">Figure 7</a>	0.5	1.4	3.0	ns
t <sub>PHZ</sub>	HIGH to OFF-state propagation delay	n $\overline{OE}$ to nQn; see <a href="#">Figure 7</a>	1.5	2.9	4.2	ns
t <sub>PLZ</sub>	LOW to OFF-state propagation delay	n $\overline{OE}$ to nQn; see <a href="#">Figure 7</a>	1.5	2.4	3.4	ns
t <sub>su</sub>	set-up time	nDn to nCP; HIGH; see <a href="#">Figure 6</a>	1.5	0.1	-	ns
		nDn to nCP; LOW; see <a href="#">Figure 6</a>	1.5	0.1	-	ns
t <sub>h</sub>	hold time	nDn to nCP; HIGH; see <a href="#">Figure 6</a>	0.5	0.1	-	ns
		nDn to nCP; LOW; see <a href="#">Figure 6</a>	0.5	0.1	-	ns
t <sub>w</sub>	pulse width	nCP HIGH; see <a href="#">Figure 5</a>	1.5	-	-	ns
		nCP LOW	1.5	-	-	ns
f <sub>max</sub>	maximum frequency	nCP; see <a href="#">Figure 5</a>	150	-	-	MHz

[1] All typical values for V<sub>CC</sub> = 2.5 V ± 0.2 V are measured at V<sub>CC</sub> = 2.5 V and T<sub>amb</sub> = 25 °C.  
 All typical values for V<sub>CC</sub> = 3.3 V ± 0.3 V are measured at V<sub>CC</sub> = 3.3 V and T<sub>amb</sub> = 25 °C.

### 10.1 Waveforms and test circuit



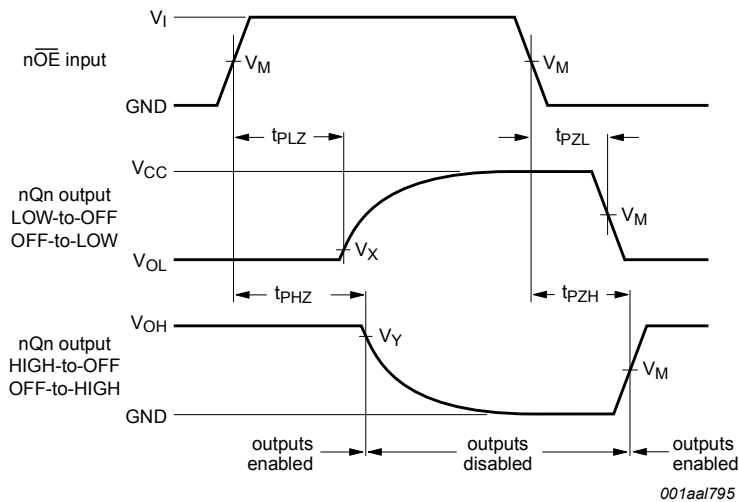


Measurement points are given in [Table 8](#).

$V_{OL}$  and  $V_{OH}$  are typical voltage output levels that occur with the output load.

The shaded areas indicate when the input is permitted to change for predictable output performance.

**Figure 6. Set-up times and hold times data input (nDn) to clock input (nCP)**



Measurement points are given in [Table 8](#).

$V_{OL}$  and  $V_{OH}$  are typical voltage output levels that occur with the output load.

**Figure 7. OFF-state to HIGH and LOW propagation delays and LOW and HIGH to OFF-state propagation delays**

**Table 8. Measurement points**

$V_{CC}$	Input	Output		
	$V_M$	$V_M$	$V_X$	$V_Y$
$V_{CC} \leq 2.7 \text{ V}$	$0.5 \times V_{CC}$	$0.5 \times V_{CC}$	$V_{OL} + 0.15 \text{ V}$	$V_{OH} - 0.15 \text{ V}$
$V_{CC} \geq 3.0 \text{ V}$	1.5 V	1.5 V	$V_{OL} + 0.3 \text{ V}$	$V_{OH} - 0.3 \text{ V}$

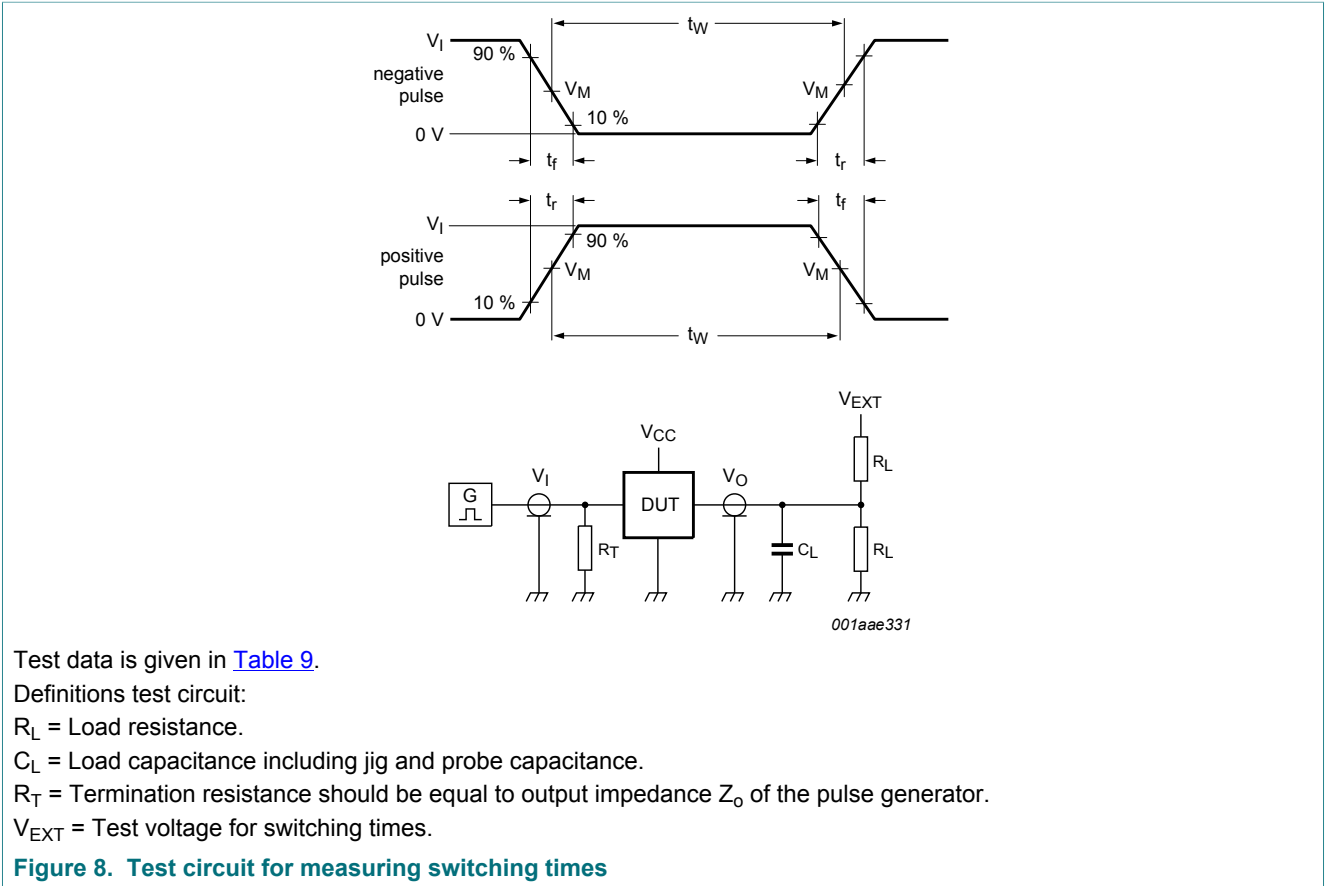


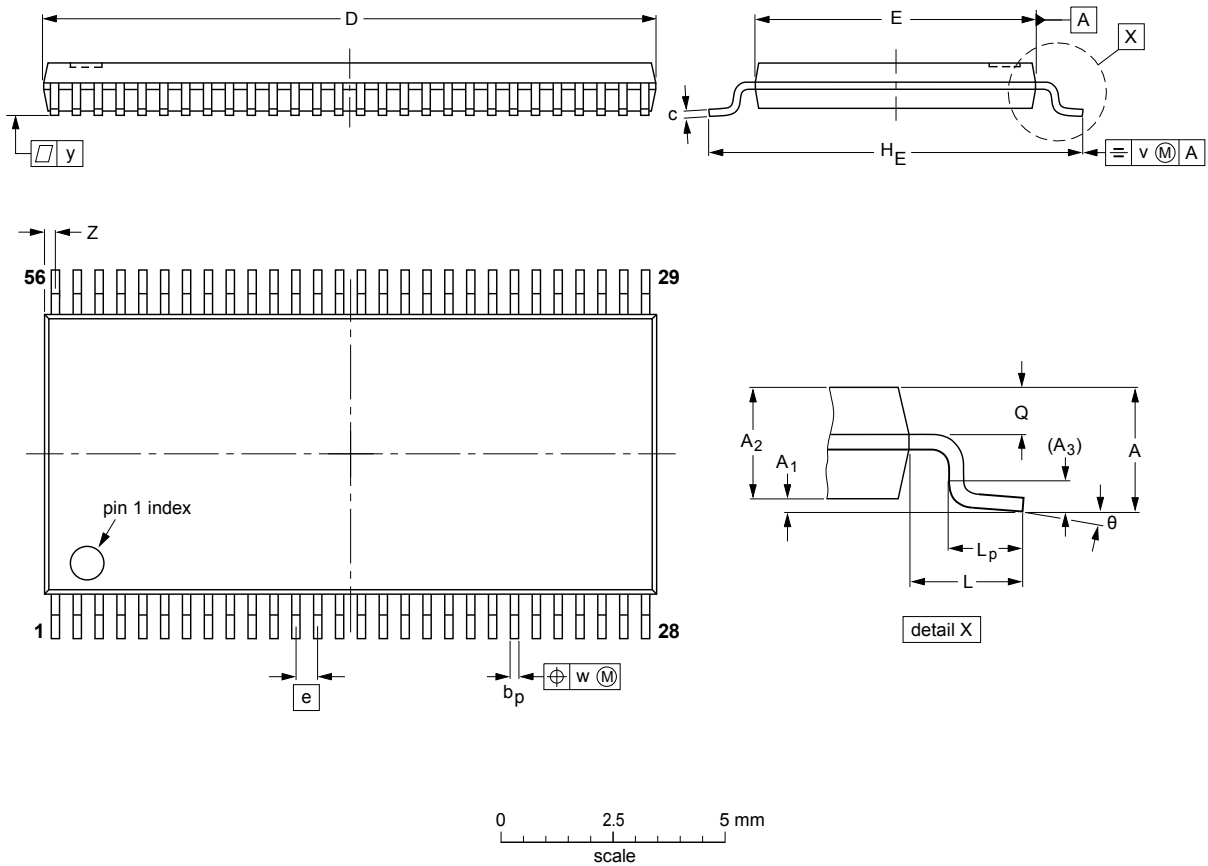
Table 9. Test data

Input		Load				$V_{EXT}$		
$V_I$	$f_i$	$t_W$	$t_r, t_f$	$C_L$	$R_L$	$t_{PHZ}, t_{PZH}$	$t_{PLZ}, t_{PZL}$	$t_{PLH}, t_{PHL}$
3.0 V or $V_{CC}$ whichever is less	$\leq 10$ MHz	500 ns	$\leq 2.5$ ns	50 pF	500 $\Omega$	GND	6 V or $V_{CC} \times 2$	open

11 Package outline

TSSOP56: plastic thin shrink small outline package; 56 leads; body width 6.1 mm

SOT364-1



DIMENSIONS (mm are the original dimensions).

UNIT	A max.	A <sub>1</sub>	A <sub>2</sub>	A <sub>3</sub>	b <sub>p</sub>	c	D <sup>(1)</sup>	E <sup>(2)</sup>	e	H <sub>E</sub>	L	L <sub>p</sub>	Q	v	w	y	Z	θ
mm	1.2	0.15 0.05	1.05 0.85	0.25	0.28 0.17	0.2 0.1	14.1 13.9	6.2 6.0	0.5	8.3 7.9	1	0.8 0.4	0.50 0.35	0.25	0.08	0.1	0.5 0.1	8° 0°

Notes

1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.
2. Plastic interlead protrusions of 0.25 mm maximum per side are not included.

OUTLINE VERSION	REFERENCES			EUROPEAN PROJECTION	ISSUE DATE
	IEC	JEDEC	JEITA		
SOT364-1		MO-153			99-12-27 03-02-19

Figure 9. Package outline SOT364-1 (TSSOP56)

## 12 Abbreviations

Table 10. Abbreviations

Acronym	Description
BICMOS	Bipolar Complementary Metal Oxide Semiconductor
DUT	Device Under Test
ESD	ElectroStatic Discharge
MIL	Military
MM	Machine Model
MOS	Metal Oxide Semiconductor

## 13 Revision history

Table 11. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
74ALVT16821 v.4	20180122	Product data sheet	-	74ALVT16821 v.3
Modifications:	<ul style="list-style-type: none"> <li>The format of this data sheet has been redesigned to comply with the identity guidelines of Nexperia.</li> <li>Legal texts have been adapted to the new company name where appropriate.</li> <li>Type number 74ALVT16821DL (SOT371-1 / SSOP56) removed.</li> </ul>			
74ALVT16821 v.3	20050613	Product data sheet	-	74ALVT16821 v.2
Modifications:	<ul style="list-style-type: none"> <li>The format of this data sheet has been redesigned to comply with the new presentation and information standard of Philips Semiconductors.</li> <li><a href="#">Section 2</a>: modified 'JEDEC Std 17' into 'JESD78'.</li> <li><a href="#">Section 9</a>: changed maximum values of propagation delay, output enable time and output disable time.</li> </ul>			
74ALVT16821 v.2	19980213	Product specification	-	74ALVT16821 v.1
74ALVT16821 v.1	19970501	Product specification	-	-

## 14 Legal information

### 14.1 Data sheet status

Document status <sup>[1][2]</sup>	Product status <sup>[3]</sup>	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions".

[3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL <http://www.nexperia.com>.

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